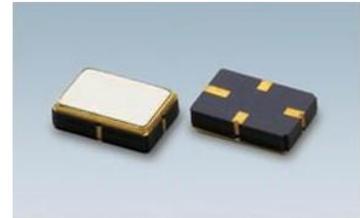


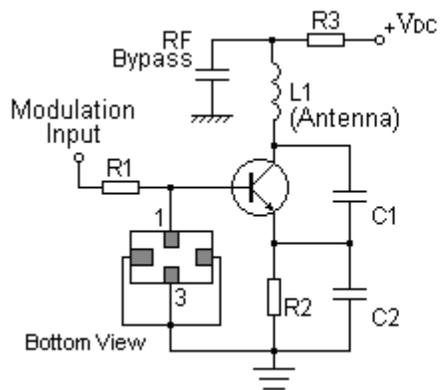
**Features**

- Ceramic Package for **Surface Mounted Technology (SMT)**
- **RoHS** compatible
- Package size 5.00x3.50x1.50mm<sup>3</sup>
- Package Code QCC4A

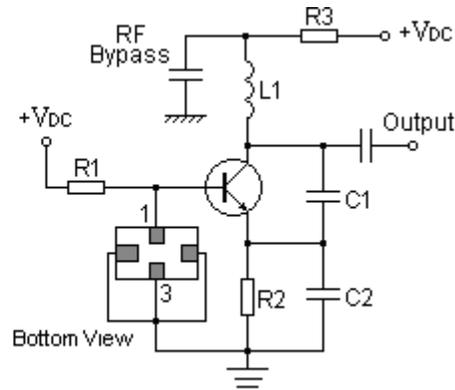


**Application**

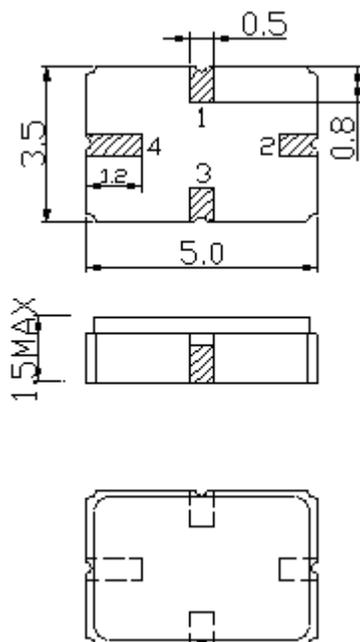
Typical Low-Power Transmitter Application



Typical Local Oscillator Application



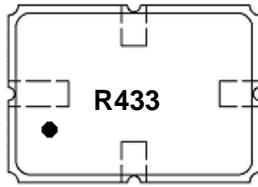
**Package Dimensions (QCC4A)**



**Pin Configuration**

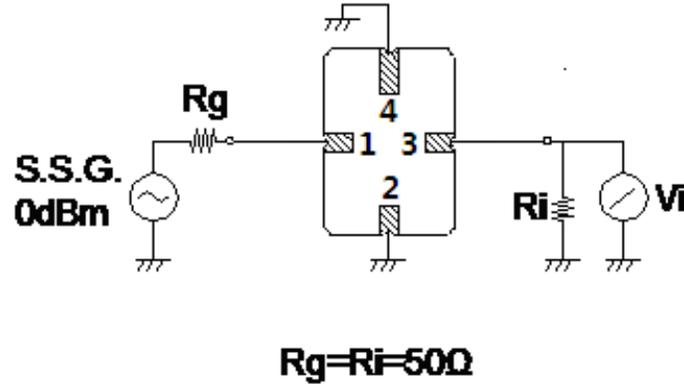
Pin No.	Description
1	Input/Output
3	Output/Input
2,4	Case Ground

## Marking Description

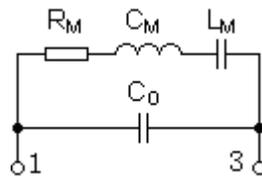


●	Pin 4
R	SAW Resonator
433	Part Number

## Test Circuit



## Equivalent LC Model



## Performance

### Maximum Rating

Item		Value	Unit
DC Voltage	$V_{DC}$	$\pm 30$	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	$T_{stg}$	-40 ~ +85	°C
RF Power Dissipation	P	15	dBm

## Electronic Characteristics

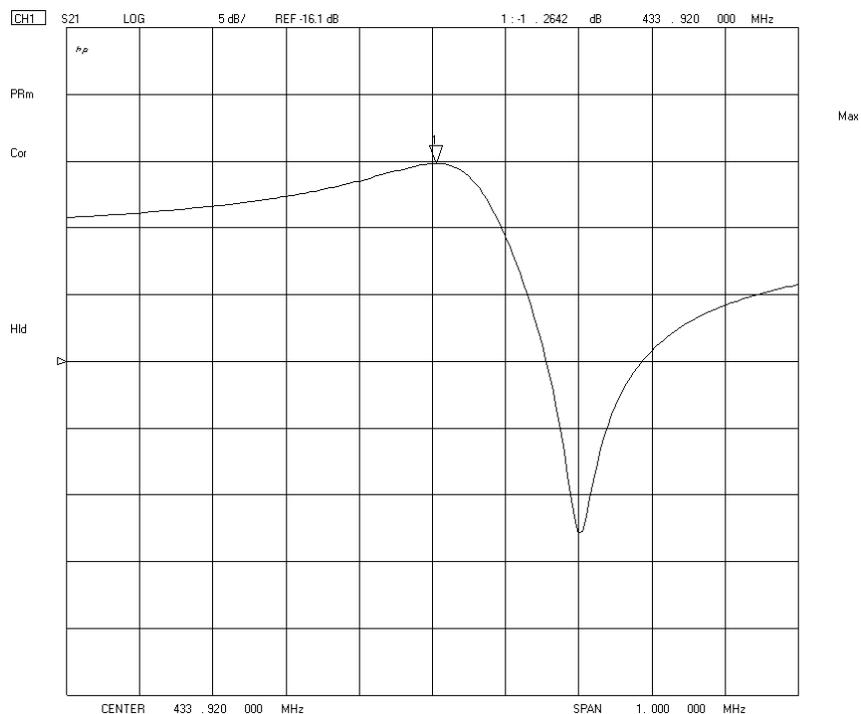
Test Temperature: 25°C±2°C

Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

Item			Minimum	Typical	Maximum	Unit
Center Frequency	Absolute Frequency	$f_c$		433.92		MHz
	Tolerance from 433.92MHz	$\Delta f_c$		±75		KHz
Insertion Loss(min)		IL		1.3	1.8	dB
Quality Factor	Unloaded Q	$Q_U$		15174		
	50Ω Loaded Q	$Q_L$		1771		
Frequency Aging	Absolute Value during the First Year	$ f_A $		≤10		ppm/yr
DC Insulation Resistance between Any Two Pins			1.0			MΩ
RF Equivalent RLC Model	Motional Resistance	$R_M$		13.0	22.0	Ω
	Motional Inductance	$L_M$		73.6		μH
	Motional Capacitance	$C_M$		1.83		fF
	Static Capacitance	$C_0$	2.1	2.4	2.7	pF

## Frequency Response





## Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.